



CT-NANO

The CT-NANO is a fully operating scanning electron microscope with capabilities of Nano-CT measurements on specimen like light-metal-alloys and fiber composites.

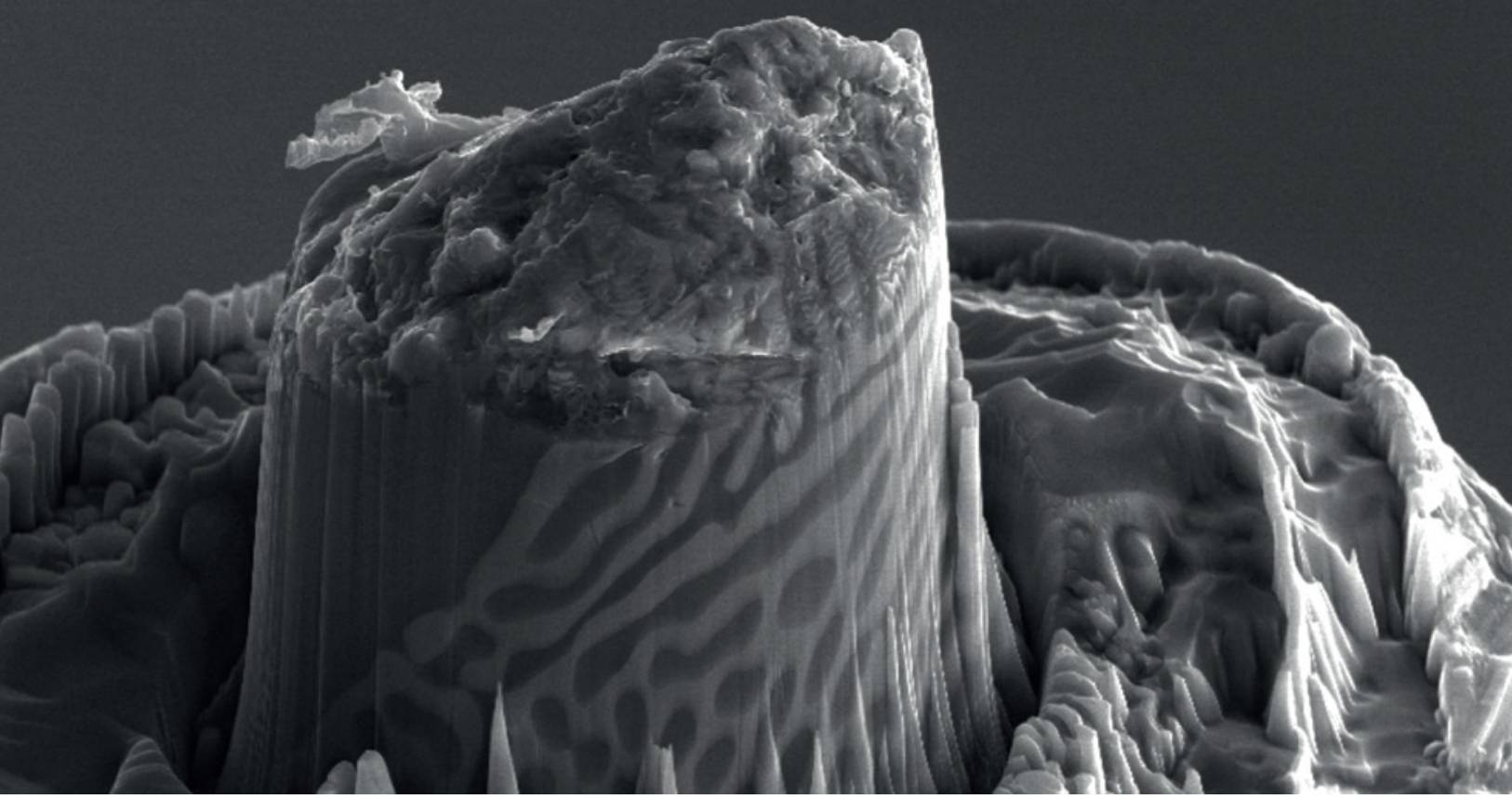
It delivers Voxel-sizes in ranges from 30 nm to 10 μm , a geometrical magnification up to 50nm (FWHM) and a maximum photon energy of 30 keV. An EDS-Detector provides an additional correlation between XRF signal of specimen and reconstructed volume of the CT-NANO.

With a direct-converting detector and a size-optimized field-of-view, the CT-NANO provides a representative test volume.

The CT-NANO X-ray microscope is based on a scanning electron microscope and uses its X-ray source.

Within the specimen chamber, the high-precision manipulator for movement of specimen and target is located.

Explore new possibilities for visualisation with 3D X-ray imaging for materials research, life sciences, natural resources, and industrial applications.



X-RAY-SOURCE

Voltage [kV]	up to 30
Current [nA]	300
Target	W, Mo

DETECTOR

Type	cooled, direct CCD
Pixel	up to 4096 x 4096
Pixelsize [μm]	15
Active Area	up to 96 x 96 mm

MANIPULATOR

improved axis-system with nm resolution
automated image alignment

SCAN PARAMETER

FieldOf View [μm]	up to 120 - 40.000
Geometric Mag.	1.5 - 500x
Voxelsampling [nm]	30 - 10.000
Resolution [nm]	<50 with needle target <500 with foil target

ProCon X-Ray GmbH
Ludwig-Erhard-Ring 6A
31157 Sarstedt
Germany

Phone +49 (0) 5066 – 98414-0
Fax +49 (0) 5066 – 98414-99
<http://www.procon-x-ray.de>
sales@procon-x-ray.de